

<b>Notice of References Cited</b>	Application/Control No. 09/932,086	Applicant(s)/Patent Under Reexamination FARKAS ET AL.	
	Examiner Guy J. Lamarre, P.E.	Art Unit 2133	Page 1 of 1

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	B	US-6,510,398	01-2003	Kundu et al.	702/117
	C	US-5,872,793	02-1999	Attaway et al.	714/726
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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